

Optimizing Embedded SSDs: One size doesn't fit all Prevention-Report-Analysis

Flash Memory Summit 2016
ATP Electronics, Inc.

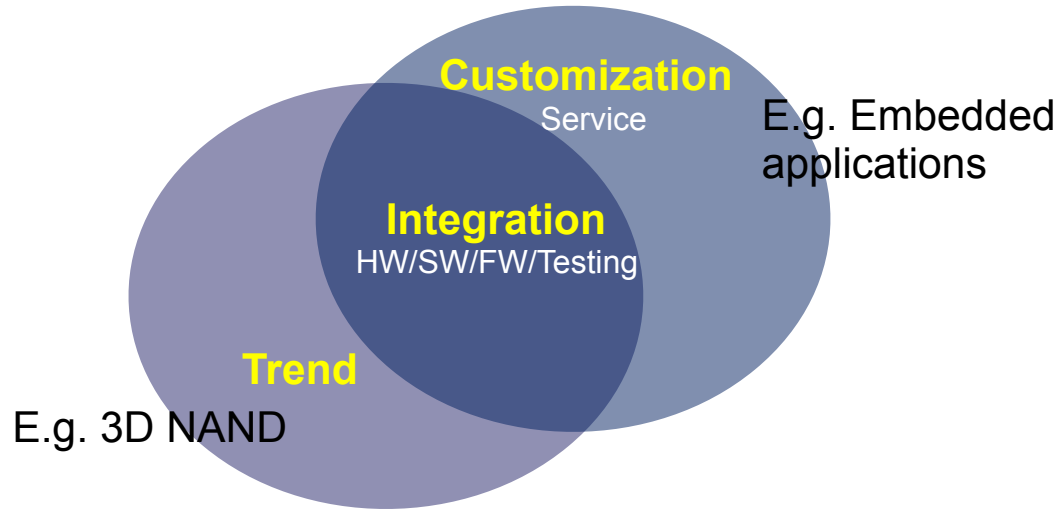
- Overview
- Embedded Applications
- Moving to 3D NAND
- The Power of Synergy - Integration
 - - Scenario 1 : Optimizing performance
 - - Scenario 2 : Power Issues
 - - Scenario 3 : Temperature Impacts
- Customization

One size doesn't fit all - The power of Synergy

Myth - “Killer feature”, “More is better”?

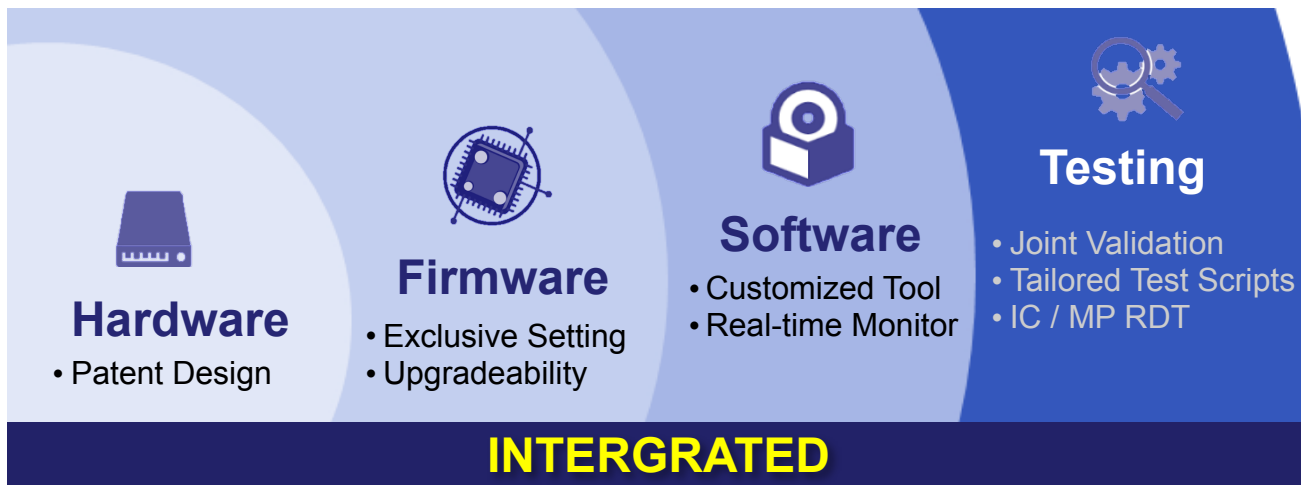
Reality - One size doesn't fit all, especially for industrial business

No killer feature can solve all problems due to various **use models, applications, and requirements**



Integration - The Power of Synergy

Seamlessly integrated state-of-art technologies with early validation makes **Preventing-Reporting-Analyzing** mechanism fully realizable.



Field Experiences in Embedded Applications...

1. Clients are interested in real-time performance
2. Most workloads are random in nature
3. Real usage :
 - **SSD as boot drives or storing application programs**
 - **Read applications**
 - **Data logging for a small set of tasks**
 - **Smaller density requirements, smaller file size data transfers**
 - **New O/S support 4K/sector architecture**
 - **4K random read/write is the key performance indicator**

Moving to 3D NAND...

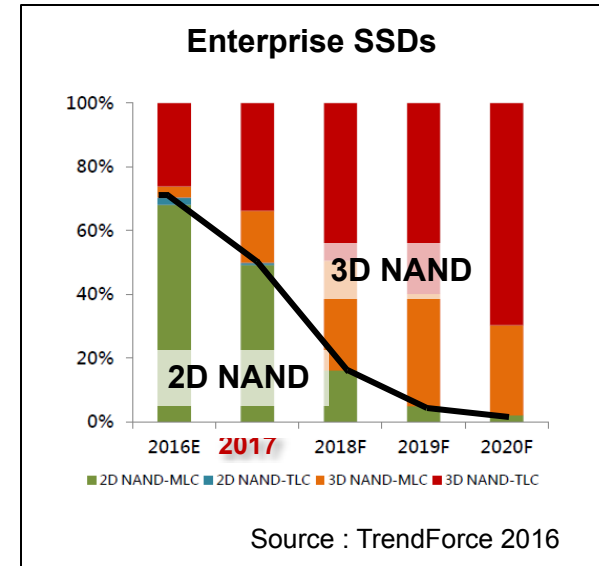
- Driven by big data / cloud computing / data center

...

- Suffering ...

- NAND Technology : Shrinking Lithographies
 - (2D, now approaching its physical limits)

- Customers' pain points :
 - Mass storage within Limited spaces
 - High Performance at the lowest Cost



▪ Mainstream focuses:

- Greater Storage Capacity (Terabytes)
- Higher Performance (IOPS ; MB/s)
- Access Latency (μ s)
- Endurance (DWPD)
- Power Consumption (W)
- Cost

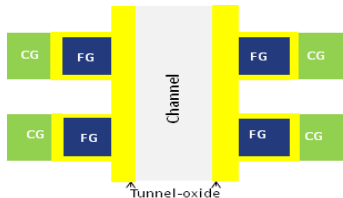
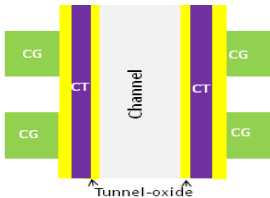
What about the real concerns of embedded applications?

p? All of above (asking for large density?)

p✓ Data Retention? Read disturb?

p What else?

- FGF/CTF...What's better for your embedded application?

	Floating Gate Flash	Charge Trap Flash
		
Endurance	Spec 3K P/E cycles (the real endurance may reach 10K~30K P/E cycles with LDPC)	Better
Read/Program Disturb	Less impact	
Data Retention	Better	

Read-intensive application

Moving to 3D NAND...

- “More” should be taken into considerations...
- **Performance issues**
 - → Capacity demands (low density) do not change
 - → But the performance has certain prerequisites (High random 4K IOPS)
- **Power issues**
 - → Power efficiency
 - → Power failure Protection / Power Risk Management
- **Temperature impacts**
 - → Reliability in industrial Temperature (-40°C ~+85°C)
 - → High temperature vs Data Retention



The Power of Synergy

Scenario1 : Optimizing performance

Tendencies

NAND Flash Evolution

→ Dies density growing to pursue larger density for cost/GB

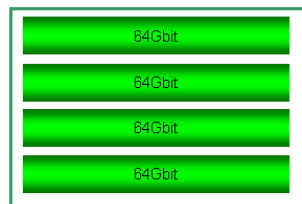
Embedded applications

→ Performance can't be compromised

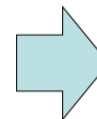
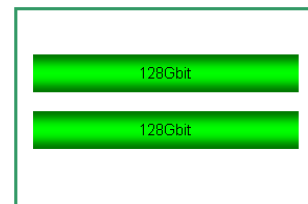
Scenario1 : Optimizing performance



20nm 32GB Embedded SSD



16nm 32GB Embedded SSD



The Power of Synergy

Scenario 2 : Power Issues

Tendencies

NAND Flash Evolution

- Better power efficiency of 3D NAND?
- Real testing data: Power consumption of 3D NAND is larger than that of 2D NAND (especially the peak current)

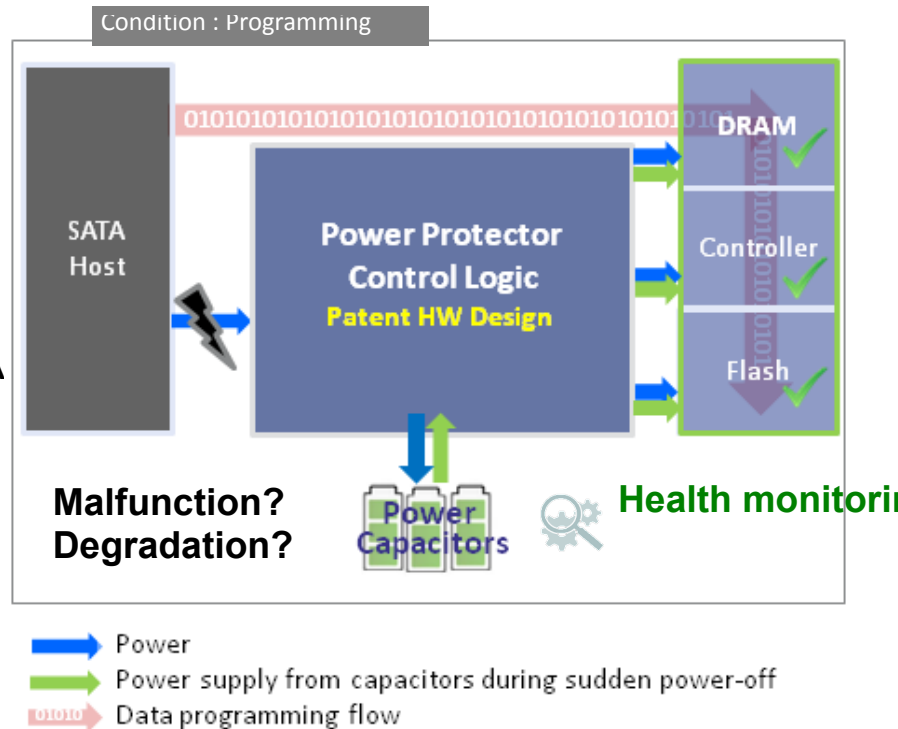
Embedded applications

- PLP (Power Loss Protection) has become the hard requirement in most cases
- Built-in capacitors in one of the approach
- No Industrial standard or criteria of PLP

Power Protector Control System

Variable design features important for PLP reliability

- Self-contained power protector
- The type of capacitors
- Broader coverage (controller/DRAM cache/NA flash)
- Overvoltage and overcurrent protection
- Power capacitor self-test mechanism
- Capacitor life monitoring

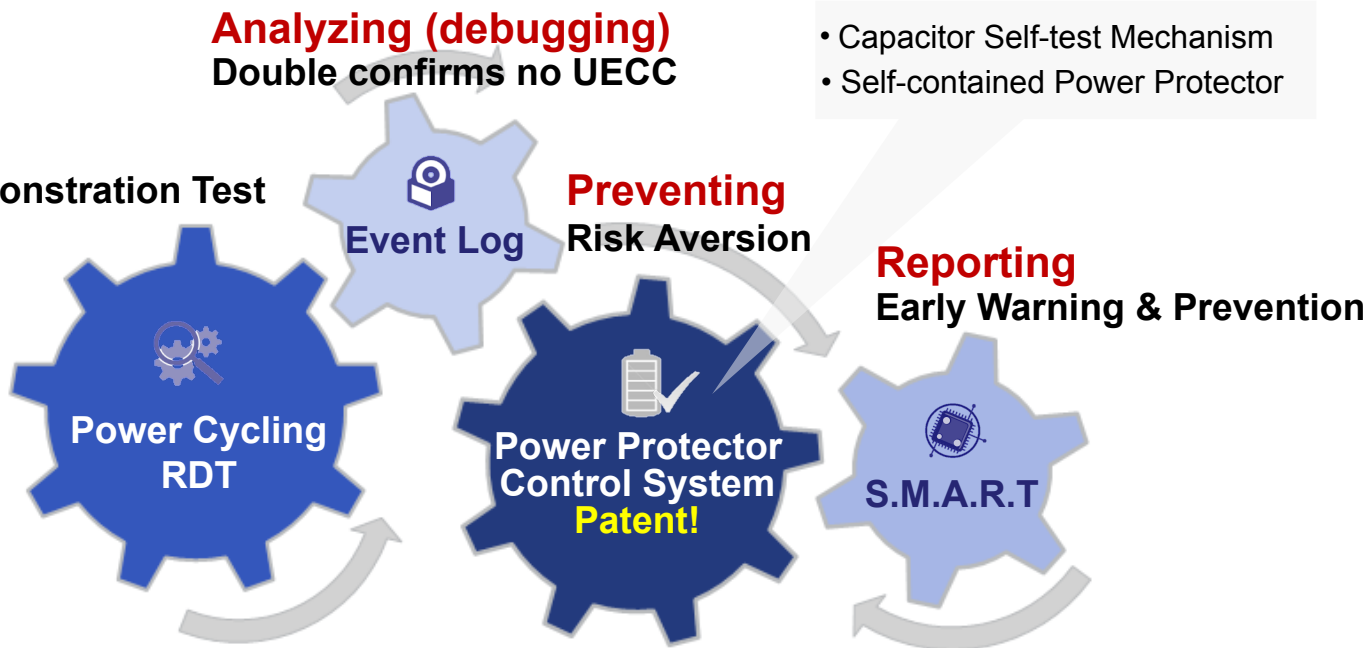


Prevention (the ultimate objective)

How it works? Evidence!

Validation

Reliability Demonstration Test
(> 5000 cycles)



The Power of Synergy

Scenario 3 : Temperature Impacts

Tendencies

NAND Flash Evolution

→ The reliability & data retention of 3D NAND?

High temperature V.S. NAND characteristics: Testing to understand the NAND nature?

Embedded applications

→ Require **Industrial Temperature** (-40°C~+85°C)?

→ Heavy workloads

→ Limited space with heat dissipation issue

→ Running 24/7

The Power of Synergy

Scenario 3 : Temperature Impacts

Conditions

- Constraint space with heat dissipation issue
- Heavy workloads
- Long-period operation
- High host device temp.

Result in...



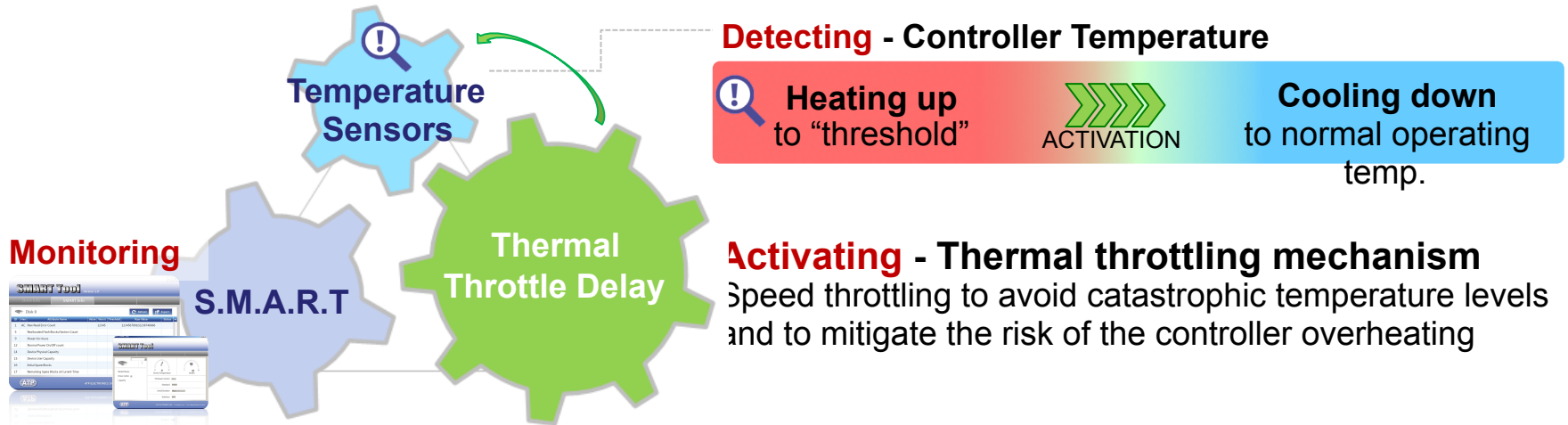
**Controller /
NAND
Overheating**

Risks

- Data loss
- Commands misinterpreted
- The OS can't be accessed
- Fail/Dead flash drive
- Malfunction

Prevention (the ultimate objective)

How it works?



Optimizing SSDs? Power of Synergy

Well Integrated & Built your specifications

- **TCO Evaluation**

Evaluate the total cost of the solution (values), rather than the purchase price alone
(BOM control, replacement, field return, reputation...etc)

- **Product Customization**

Hardware design /Firmware setting/ Custom Label
Customizability of S.M.A.R.T attributes for specific customer analysis/debug/use case

- **Validation**

Tailored Test criteria with specific scripts/software
Joint Validation & Qualification to ensure reliability during the life cycle of the product

TCO



Product



Validation



Meet Your sustainability goals

One size doesn't fit all

Pick out what you really need based on your application!

- ✓ There are no killer features, only the feature that can fit your applications or not.
- ✓ Moving to 3D NAND...more influences should be counted.
- ✓ **Integration (Synergy) : Prevention-Report-Analysis**
A cycle of prevention-report-analysis for risk management and continuous improvement
- ✓ **Optimizing SSD** : meet requirements with **low TCO**

Thank you !

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